



# STM302N060USH8H

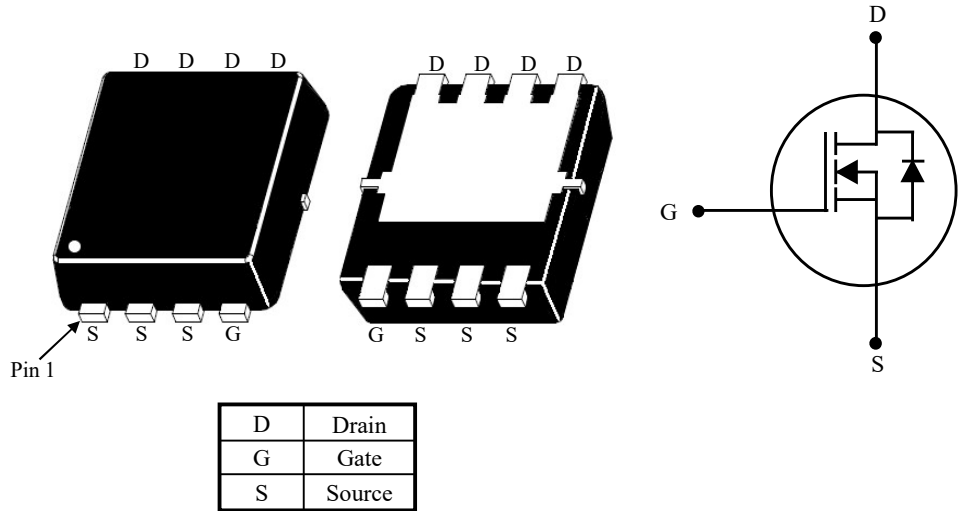
## N-Channel Enhancement Mode Field Effect Transistor

### FEATURES

· Suffix "H" indicates Halogen-free parts, ex. STM302N060USH8H

### PIN CONFIGURATION

DFN3×3-8L



### Maximum Ratings ( $T_A = 25\text{ }^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Value	Unit	
Drain-Source Voltage	$V_{DS}$	20	V	
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V	
Drain Current	$I_D$	$T_C = 25\text{ }^\circ\text{C}$	63.0	A
		$T_C = 100\text{ }^\circ\text{C}$	39.7	
Pulsed Drain Current (Note 1)	$I_{DM}$	250	A	
Avalanche Current	$I_{AS}$	35	A	
Avalanche Energy (Note 2)	$E_{AS}$	61.2	mJ	
Power Dissipation	$P_D$	29	W	
Thermal Resistance from Junction to Ambient (Note 3)	$R_{\theta JA}$	60	$^\circ\text{C}/\text{W}$	
Thermal Resistance from Junction to Case	$R_{\theta JC}$	4.3	$^\circ\text{C}/\text{W}$	
Operating and Storage Temperature Range	$T_J, T_{stg}$	- 55 to + 150	$^\circ\text{C}$	

- Note :
1. Pulse Test: Pulse Width  $\leq 100\mu\text{s}$ , Duty Cycle  $\leq 2\%$ , Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)} = 150\text{ }^\circ\text{C}$ .
  2. Limited by  $T_{J(MAX)}$ , starting  $T_J = 25\text{ }^\circ\text{C}$ ,  $L = 0.1\text{mH}$ ,  $R_g = 25\Omega$ ,  $I_{AS} = 35\text{A}$ ,  $V_{GS} = 10\text{V}$ .
  3. Device mounted on FR-4 substrate PC board, 2oz copper, with 1-inch square copper plate in still air.



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### Electrical Characteristics ( $T_A = 25\text{ }^\circ\text{C}$ unless otherwise specified)

Parameter	Conditions	Symbol	Min.	Typ.	Max.	Unit
<b>Static</b>						
Drain Source Breakdown Voltage	$I_D = 250\mu\text{A}$	$V_{(BR)DSS}$	20	-	-	V
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	$V_{GS(th)}$	0.3	-	1.0	V
Zero Gate Voltage Drain Current	$V_{DS} = 20\text{V}$	$I_{DSS}$	-	-	1	$\mu\text{A}$
Gate-Body Leakage Current	$V_{GS} = \pm 12\text{V}$	$I_{GSS}$	-	-	$\pm 0.1$	$\mu\text{A}$
Drain-Source On-State Resistance	$V_{GS} = 4.5\text{V}, I_D = 20\text{A}$	$R_{DS(on)}$	-	4.7	6.0	$\text{m}\Omega$
	$V_{GS} = 2.5\text{V}, I_D = 18\text{A}$		-	-	6.5	
Forward Transconductance	$V_{DS} = 5\text{V}, I_D = 20\text{A}$	$g_{fs}$	-	36	-	S
<b>Dynamic</b>						
Gate Resistance	$V_{DS} = 0\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$	$R_g$	-	0.7	-	$\Omega$
Total Gate Charge	$V_{DS} = 10\text{V}, V_{GS} = 2.5\text{V}, I_D = 20\text{A}$	$Q_g$	-	26	-	nC
			-	44	-	
Gate-Source Charge	$V_{DS} = 10\text{V}, V_{GS} = 4.5\text{V}, I_D = 20\text{A}$	$Q_{gs}$	-	5	-	
Gate-Drain Charge		$Q_{gd}$	-	15	-	
Input Capacitance	$V_{DS} = 10\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$	$C_{iss}$	-	2619	-	pF
Output Capacitance		$C_{oss}$	-	388	-	
Reverse Transfer Capacitance		$C_{rss}$	-	344	-	
Turn-On Delay Time	$V_{GS} = 4.5\text{V}, V_{DS} = 10\text{V}, I_D = 20\text{A}, R_g = 3.3\Omega$	$t_{d(on)}$	-	25	-	ns
Turn-On Rise Time		$t_r$	-	82	-	
Turn-Off Delay Time		$t_{d(off)}$	-	30	-	
Turn-Off Fall Time		$t_f$	-	8	-	
<b>Drain-Source Body Diode</b>						
Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = 1\text{A}$	$V_{SD}$	-	-	1.2	V
Diode Continuous Source Current	-	$I_S$	-	-	63	A
Diode Pulse Current	-	$I_{SM}$	-	-	250	A
Reverse Recovery Time	$I_S = 20\text{A}, di/dt = 100\text{A}/\mu\text{s}$	$t_{rr}$	-	25.9	-	ns
Reverse Recovery Charge		$Q_{rr}$	-	16.7	-	nC



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### RATINGS AND CHARACTERISTIC CURVES

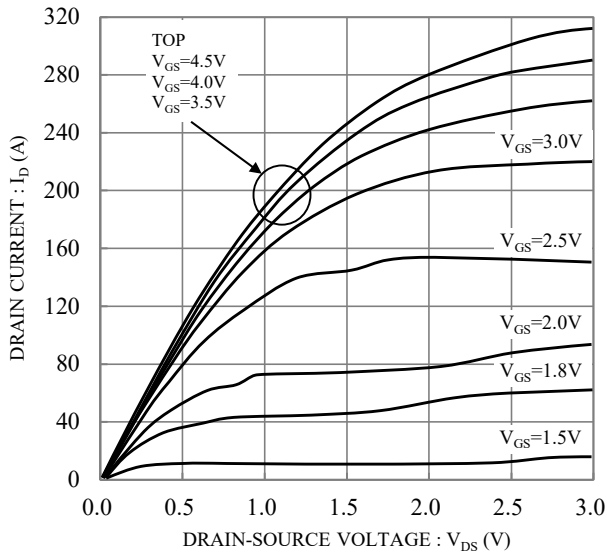


Fig.1 Typical Output Characteristics

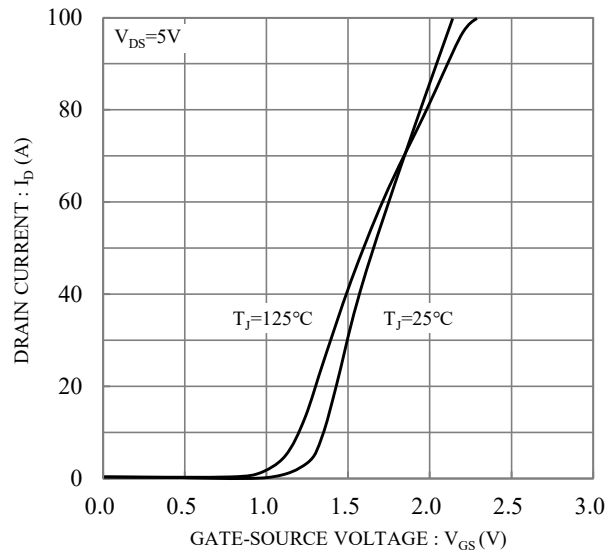


Fig.2 Typical Transfer Characteristics

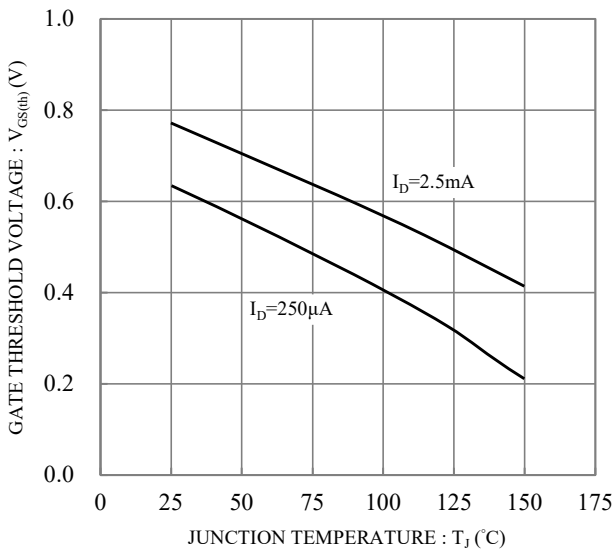


Fig.3 Gate Threshold Voltage vs. Junction Temperature

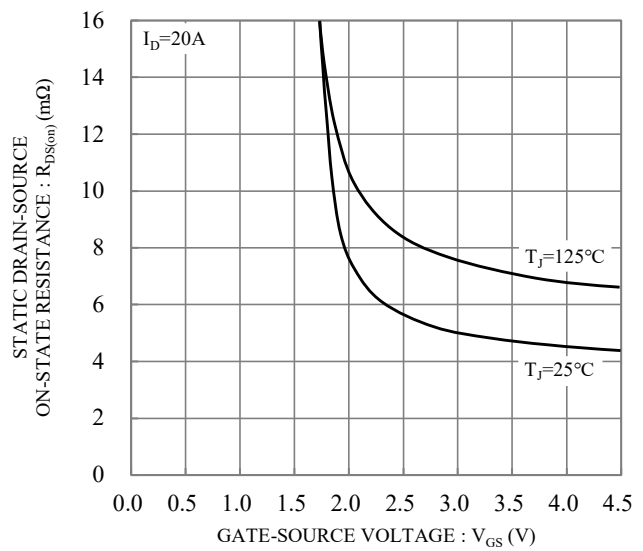


Fig.4 Static Drain-Source On-State Resistance vs. Gate-Source Voltage

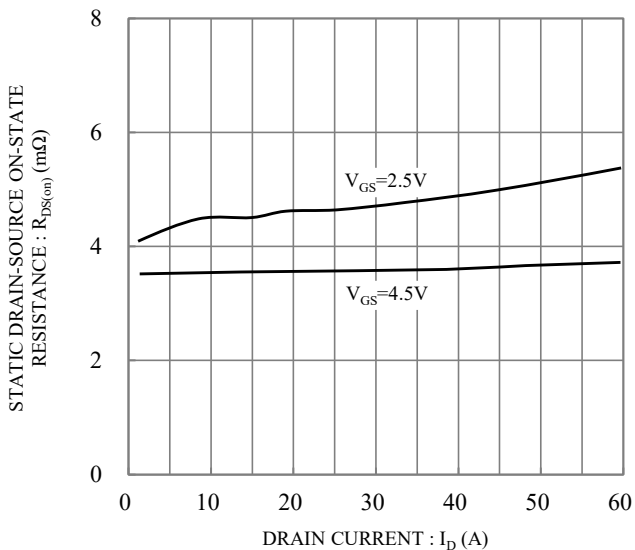


Fig.5 Static Drain-Source On-State Resistance vs. Drain Current

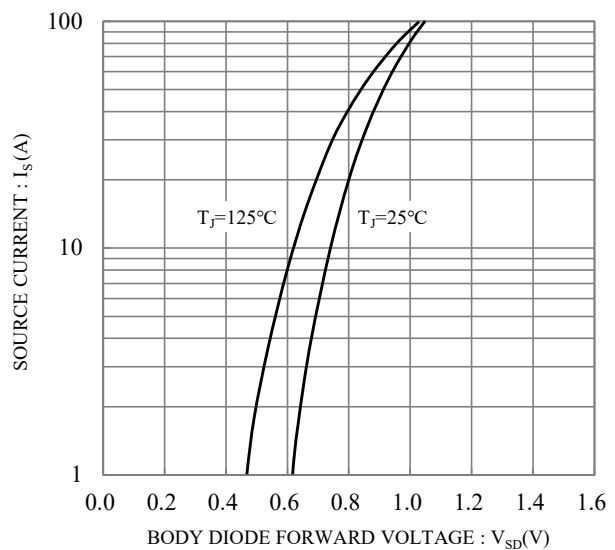
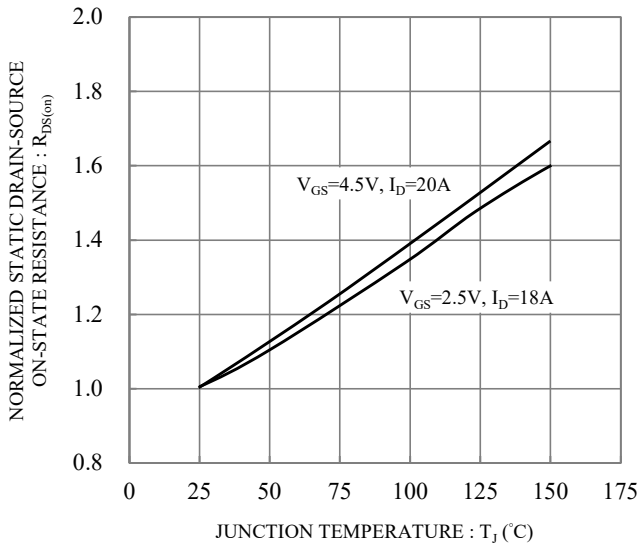


Fig.6 Body Diode Forward Voltage vs. Source Current

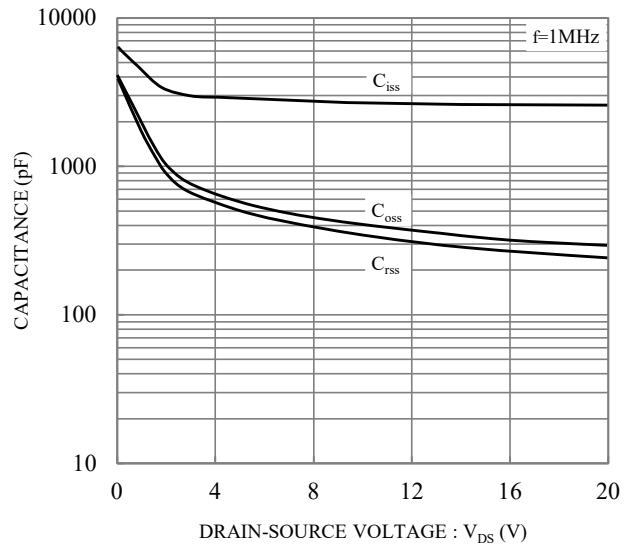


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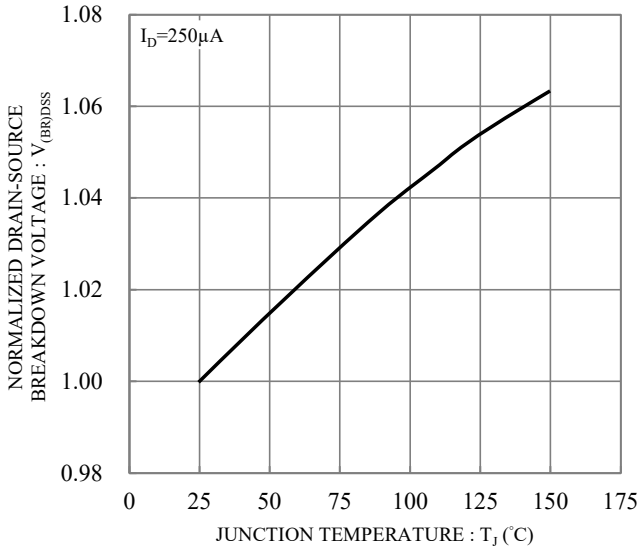
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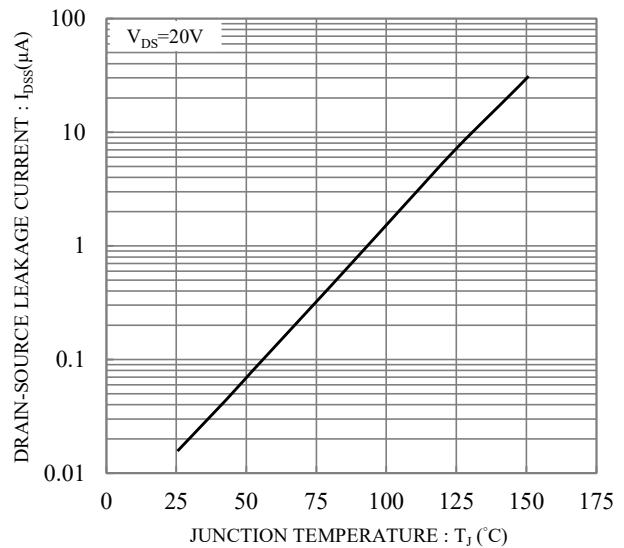
**Fig.7 Drain-Source On-State Resistance vs. Junction Temperature**



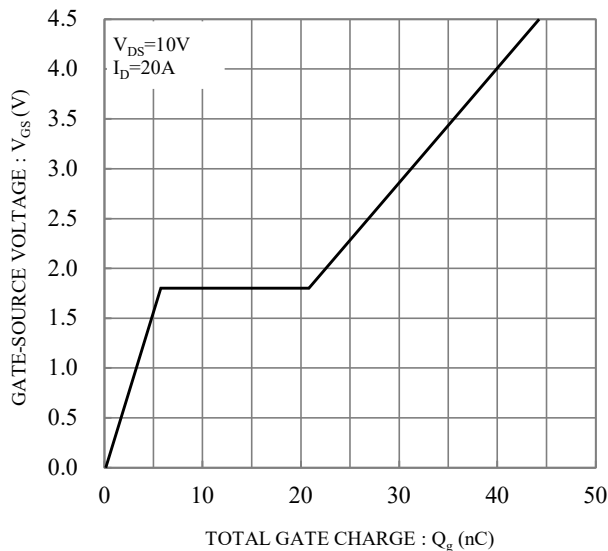
**Fig.8 Capacitance vs. Drain-Source Voltage**



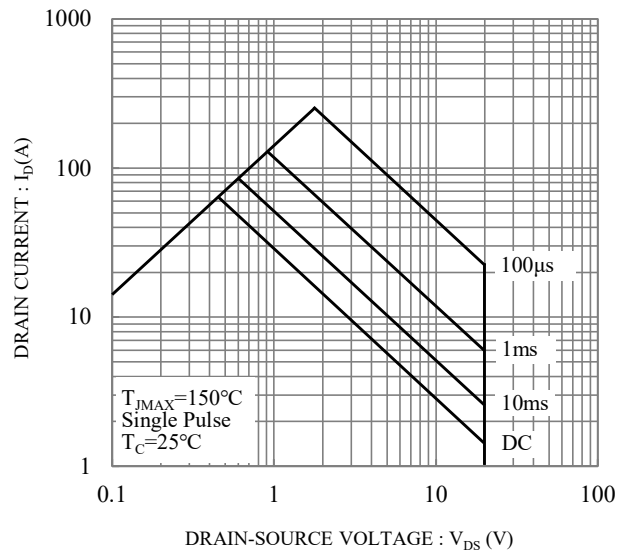
**Fig.9 Breakdown Voltage vs. Junction Temperature**



**Fig.10 Drain-Source Leakage Current vs. Junction Temperature**



**Fig.11 Gate Charge Characteristics**

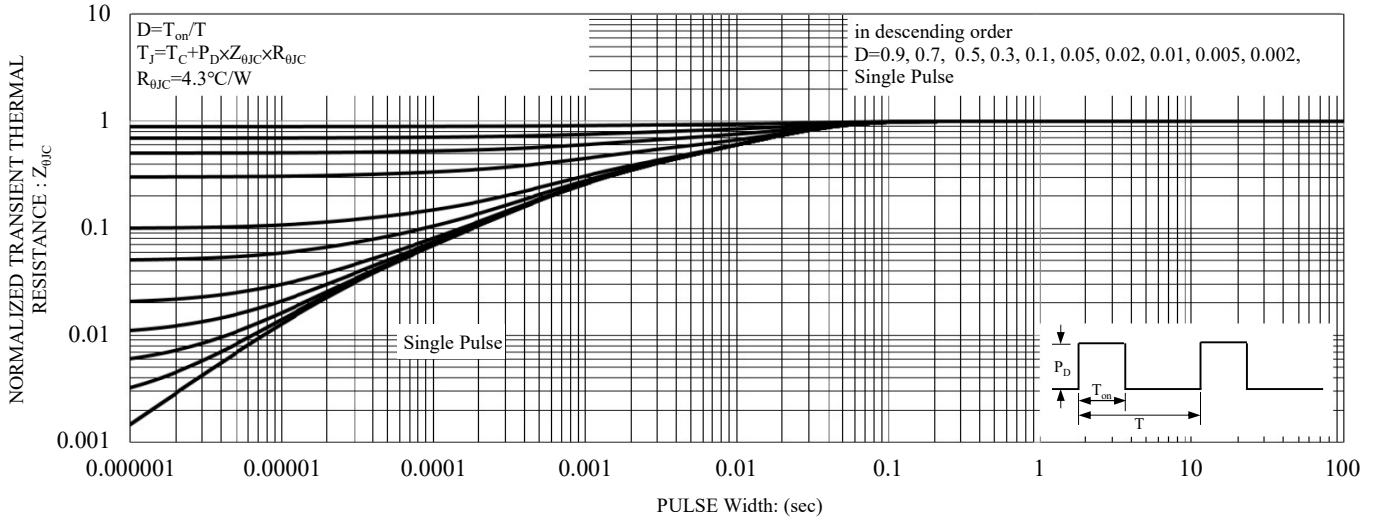


**Fig.12 Drain-Source Leakage Current vs. Junction Temperature**

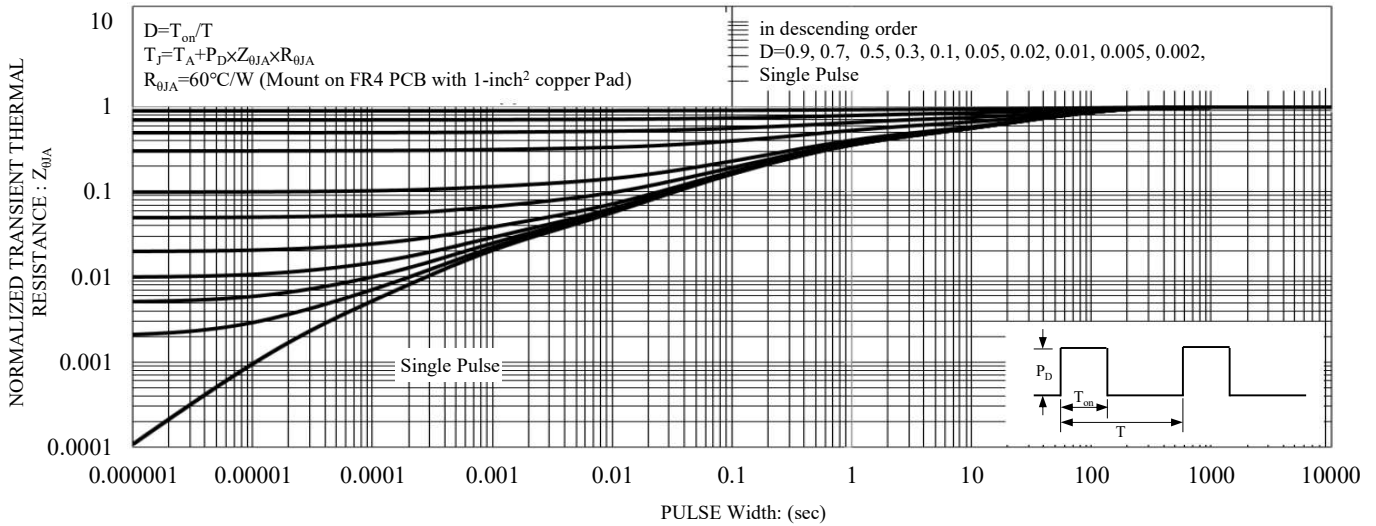


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**Fig.13 Maximum Transient Thermal Impedance**



**Fig.14 Maximum Transient Thermal Impedance**

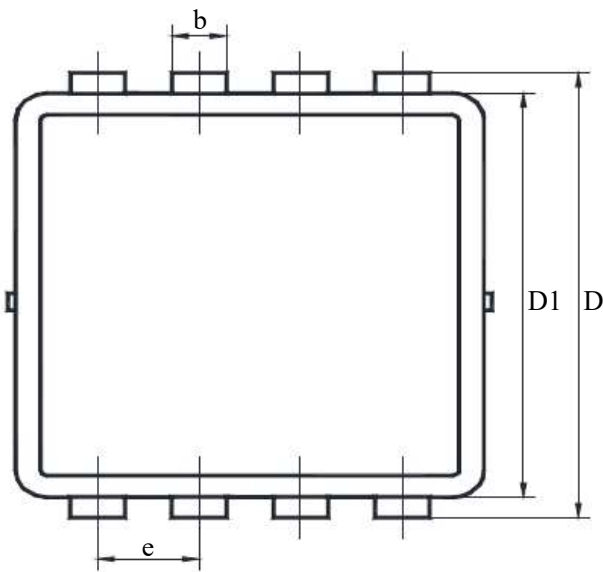


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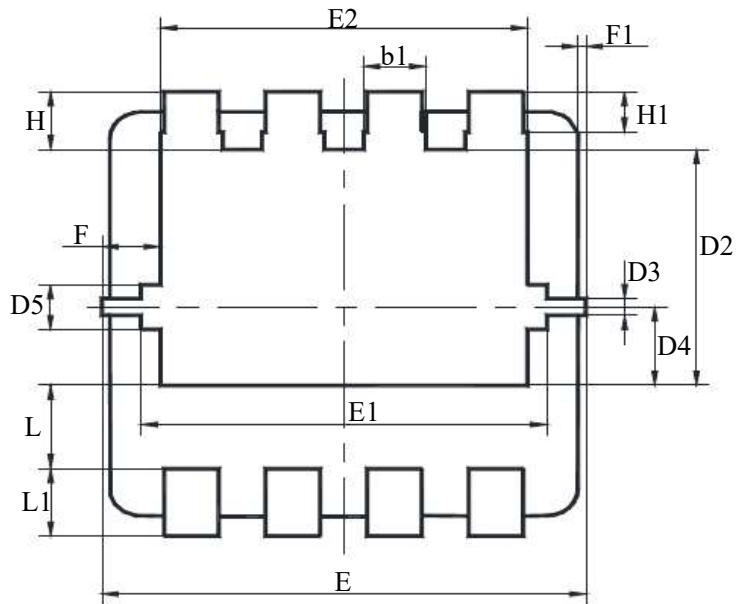
N-Channel Enhancement Mode Field Effect Transistor

## PACKAGE DIMENSION

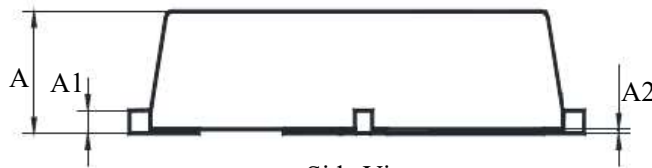
### DFN3x3-8L



Top View



Bottom View



Side View

Symbol	Millimeters		Inches	
	Min	Max	Min	Max
A	0.700	0.900	0.028	0.035
A1	0.100	0.250	0.004	0.010
A2	0.000	0.050	0.000	0.002
b	0.240	0.350	0.009	0.014
b1	0.300	0.500	0.012	0.020
D	3.100	3.300	0.122	0.130
D1	2.900	3.100	0.114	0.122
D2	1.650	1.850	0.065	0.073
D3	0.150	0.250	0.006	0.010
D4	0.480	0.680	0.019	0.027
D5	0.230	0.430	0.009	0.017
E	3.000	3.200	0.118	0.126
E1	2.500	2.700	0.098	0.106
E2	2.400	2.600	0.094	0.102
e	0.600	0.700	0.024	0.028
F	0.275	0.475	0.011	0.019
F1	0.000	0.100	0.000	0.004
L	0.520	0.720	0.020	0.028
L1	0.300	0.500	0.012	0.020
H	0.330	0.530	0.013	0.021
H1	0.200	0.400	0.008	0.016

